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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,424	QIAO ET AL.	
Examiner	Art Unit	
Paul S. Hyun	1743	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner
		 	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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